

Jonathon Cottom

List of Publications by Year in descending order

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Version: 2024-02-01

21
papers

338
citations

759233

12
h-index

888059

17
g-index

21
all docs

21
docs citations

21
times ranked

529
citing authors

#	ARTICLE	IF	CITATIONS
1	The origin of negative charging in amorphous Al ₂ O ₃ films: the role of native defects. Nanotechnology, 2019, 30, 205201.	2.6	68
2	Elucidating the Effect of Planar Graphitic Layers and Cylindrical Pores on the Storage and Diffusion of Li, Na, and K in Carbon Materials. Advanced Functional Materials, 2020, 30, 1908209.	14.9	49
3	Defects in Hard Carbon: Where Are They Located and How Does the Location Affect Alkaline Metal Storage?. Small, 2021, 17, e2007652.	10.0	28
4	Electrically detected magnetic resonance of carbon dangling bonds at the Si-face 4H-SiC/SiO ₂ interface. Journal of Applied Physics, 2018, 123, .	2.5	22
5	Computational study of the mixed B-site perovskite SmB _x Co _{1-x} O ₃ (B = Mn, Fe, Ni, Cu) for next generation solid oxide fuel cell cathodes. Physical Chemistry Chemical Physics, 2019, 21, 9407-9418.	2.8	20
6	Investigating the effect of edge and basal plane surface functionalisation of carbonaceous anodes for alkali metal (Li/Na/K) ion batteries. Carbon, 2021, 177, 226-243.	10.3	19
7	Elucidation of the Solid Electrolyte Interphase Formation Mechanism in Micro-Mesoporous Hard-Carbon Anodes. Advanced Materials Interfaces, 2022, 9, 2101267.	3.7	18
8	Recombination defects at the 4H-SiC/SiO ₂ interface investigated with electrically detected magnetic resonance and <i>ab initio</i> calculations. Journal of Applied Physics, 2018, 124, .	2.5	17
9	An oxygen vacancy mediated Ag reduction and nucleation mechanism in SiO ₂ RRAM devices. Microelectronics Reliability, 2019, 98, 144-152.	1.7	16
10	Recombination centers in 4H-SiC investigated by electrically detected magnetic resonance and <i>ab initio</i> modeling. Journal of Applied Physics, 2016, 119, .	2.5	15
11	Filling a Niche in Ligand Space with Bulky, Electron-Poor Phosphorus(III) Alkoxides. Chemistry - A European Journal, 2019, 25, 2262-2271.	3.3	15
12	Effect of electric field on defect generation and migration in HfO ₂ . Physical Review B, 2020, 102, .	3.2	14
13	Structural, elastic, vibrational and electronic properties of amorphous Sm ₂ O ₃ from Ab Initio calculations. Computational Materials Science, 2019, 169, 109119.	3.0	10
14	Combined density functional theory and molecular dynamics study of Sm _{0.75} A _{0.25} Co _{1-x} Mn _x O _{2.88} (A = Ca, Sr; Tj ETQq0 0 0 rgBT /Overl	2.8	10
15	Modeling of Diffusion and Incorporation of Interstitial Oxygen Ions at the TiN/SiO ₂ Interface. ACS Applied Materials & Interfaces, 2019, 11, 36232-36243.	8.0	9
16	Identifying Performance Limiting Defects in Silicon Carbide pn-Junctions: A Theoretical Study. Materials Science Forum, 0, 858, 257-260.	0.3	2
17	First Principles Study of the Influence of the Local Steric Environment on the Incorporation and Migration of NO in a-SiO ₂ . Materials Science Forum, 2019, 963, 194-198.	0.3	2
18	The nature of column boundaries in micro-structured silicon oxide nanolayers. APL Materials, 2021, 9, 121107.	5.1	2

#	ARTICLE	IF	CITATIONS
19	Theoretical Study of Ag Interactions in Amorphous Silica RRAM Devices. , 2018, , .		1
20	Evidence for an Abrupt Transition between SiO ₂ and SiC from EELS and Ab Initio Modelling. Materials Science Forum, 0, 963, 199-203.	0.3	1
21	Elucidation of the Solid Electrolyte Interphase Formation Mechanism in Micro-Mesoporous Hard-Carbon Anodes (Adv. Mater. Interfaces 8/2022). Advanced Materials Interfaces, 2022, 9, .	3.7	0